

MOSFET

Metall Oxide Semiconductor Field Effect Transistor

CoolMOS E6

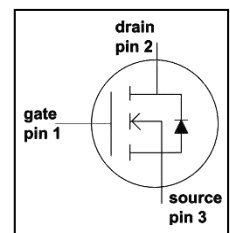
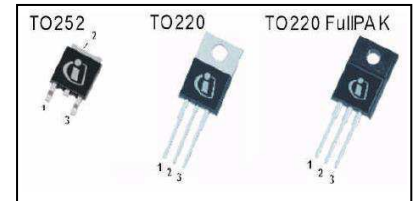
650V CoolMOS™ E6 Power Transistor
IPx65R600E6

Data Sheet

Rev. 2.4
Final

1 Description

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. CoolMOS™ DE series combines the experience of the leading SJ MOSFET supplier with high class innovation. The resulting devices provide all benefits of a fast switching SJ MOSFET while not sacrificing ease of use. Extremely low switching and conduction losses make switching applications even more efficient, more compact, lighter, and cooler.



Features

- Extremely low losses due to very low FoM $R_{DS(on)} \cdot Q_g$ and E_{oss}
- Very high commutation ruggedness
- Easy to use/drive, Pb-free plating, Halogen free mold compound
- Fully qualified according to JEDEC for Industrial Applications

Applications

PFC stages, hard switching PWM stages and resonant switching PWM stages e.g. PC Silverbox, Adapter, LCD & PDP TV, Lightning, Server, Telecom and UPS.

Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.



Table 1 Key Performance Parameters

| Parameter | Value | Unit |
|-----------------------|-------|------------|
| $V_{DS} @ T_{j, max}$ | 700 | V |
| $R_{DS(on), max}$ | 0.6 | Ω |
| Q_G, typ | 23 | nC |
| $I_D, pulse$ | 18 | A |
| $E_{oss} @ 400V$ | 2 | μJ |
| Body diode di/dt | 500 | A/ μs |

| Type / Ordering Code | Package | Marking | Related links |
|----------------------|------------------|---------|---|
| IPD65R600E6 | PG-TO252 | 65E6600 | IFX CoolMOS Webpage IFX Design tools |
| IPP65R600E6 | PG-TO220 | | |
| IPA65R600E6 | PG-TO220 FullPAK | | |

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2 Maximum ratings

At $T_j = 25^\circ\text{C}$, unless otherwise specified.

Table 2 Maximum ratings

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|---|-----------------|--------|------|------|------------------|---|
| | | Min. | Typ. | Max. | | |
| Continuous drain current ¹⁾ | I_D | – | – | 7.3 | A | $T_C = 25^\circ\text{C}$ |
| | | – | – | 4.6 | | $T_C = 100^\circ\text{C}$ |
| Pulsed drain current ²⁾ | $I_{D, pulse}$ | – | – | 18 | | $T_C = 25^\circ\text{C}$ |
| Averlanche energy, single pulse | E_{AS} | – | – | 142 | mJ | $I_D = 1.3\text{A}; V_{DD} = 50\text{V};$ $T_C = 25^\circ\text{C}$ (see Table 21) |
| Averlanche energy, repetitive | E_{AR} | – | – | 0.21 | | $I_D = 1.3\text{A}, V_{DD} = 50\text{V}$ |
| Avalanche current, repetitive | I_{AR} | – | – | 1.3 | A | |
| MOSFET dv/dt ruggedness | dv/dt | – | – | 50 | V/ns | $V_{DS} = 0 \dots 480\text{V}$ |
| Gate source voltage | V_{GS} | -20 | – | 20 | V | static |
| | | -30 | | 30 | | AC ($f > 1\text{Hz}$) |
| Power dissipation for Non FullPAK | P_{tot} | – | – | 63 | W | $T_C = 25^\circ\text{C}$ |
| Power dissipation for FullPAK | P_{tot} | – | – | 28 | W | $T_C = 25^\circ\text{C}$ |
| Operating and storage temperature | T_j, T_{stg} | -55 | – | 150 | °C | |
| Mounting torque TO-220 | | – | – | 60 | Ncm | M3 and M3.5 screws |
| Mounting torque TO-220 FullPAK | | – | – | 50 | | M2.5 Screws |
| Continous diode forward current | I_S | – | – | 6.3 | A | $T_C = 25^\circ\text{C}$ |
| Diode pulse current ²⁾ | $I_{S, pulsed}$ | – | – | 18 | A | $T_C = 25^\circ\text{C}$ |
| Reverse diode dv/dt ³⁾ | dv/dt | – | – | 15 | V/ns | $V_{DS} = 0 \dots 480\text{V}, I_{SD} \leq I_D,$ |
| Maximum diode commutation speed ³⁾ | di/dt | | | 500 | A/ μs | $T_C = 125^\circ\text{C}$ (see table 22) |

1) Limited by $T_{j, max}$. Maximum duty cycle $D=0.75$

2) Pulse width t_p limited by $T_{j, max}$

3) Identical low side and high side switch with identical R_θ

3 Thermal characteristics

Table 3 Thermal characteristics TO-220 (IPP65R600E6)

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|--|------------|--------|------|------|------|--------------------------------------|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction-case | R_{thJC} | – | – | 2.0 | °C/W | leaded |
| Thermal resistance, junction-ambient | R_{thJA} | – | – | 62 | | |
| Soldering temperature, wavesoldering only allowed at leads | T_{sold} | – | – | 260 | °C | 1.6mm (0.063 in.) from case for 10 s |

Table 4 Thermal characteristics TO-220 FullPAK (IPA65R600E6)

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|--|------------|--------|------|------|------|--------------------------------------|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction-case | R_{thJC} | – | – | 4.5 | °C/W | leaded |
| Thermal resistance, junction-ambient | R_{thJA} | – | – | 80 | | |
| Soldering temperature, wavesoldering only allowed at leads | T_{sold} | – | – | 260 | °C | 1.6mm (0.063 in.) from case for 10 s |

Table 5 Thermal characteristics TO-252 (IPD65R600E6)

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|---|------------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction-case | R_{thJC} | – | – | 2.0 | °C/W | SMD version, device on PCB, minimal footprint |
| Thermal resistance, junction-ambient | R_{thJA} | – | – | 62 | | |
| | | | 35 | | | |
| Soldering temperature, wave- & reflowsoldering only allowed | T_{sold} | – | – | 260 | °C | Reflow MSL1 |

1) Device on 40mm*40mm*1.5 epoxy PCB FR4 with 6cm² (one layer, 70µm thick) copper area for drain connection. PCB is vertical without air stream cooling.

4 Electrical characteristics

Electrical characteristics, at $T_j=25^\circ\text{C}$, unless otherwise specified

Table 6 Static characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|------------------------------------|---------------|--------|------|------|---------------|--|
| | | Min. | Typ. | Max. | | |
| Drain-source Breakdown voltage | $V_{(BR)DSS}$ | 650 | – | – | V | $V_{GS}=0V, I_D=1.0mA$ |
| Gate threshold voltage | $V_{GS(th)}$ | 2.5 | 3 | 3.5 | | $V_{DS}=V_{GS}, I_D=0.21mA$ |
| Zero gate Voltage drain current | I_{DSS} | – | – | 1 | μA | $V_{DS}=600V, V_{GS}=0V,$ $T_f=25^\circ\text{C}$ |
| | | – | 10 | – | | $V_{DS}=600V, V_{GS}=0V,$ $T_f=150^\circ\text{C}$ |
| Gate- source leakage current | I_{GSS} | – | – | 100 | nA | $V_{GS}=20V, V_{DS}=0V$ |
| Drain- source on- state resistance | $R_{DS(on)}$ | – | 0.54 | 0.6 | Ω | $V_{GS}=10V, I_D=2.1A,$ $T_f=25^\circ\text{C}$ |
| | | – | 1.40 | – | | $V_{GS}=10V, I_D=2.1A,$ $T_f=150^\circ\text{C}$ |
| Gate resistance | R_G | – | 10.5 | – | Ω | $f=1\text{MHz}, \text{open drain}$ |

Table7 Dynamic characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|--|--------------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Input capacitance | C_{iss} | – | 440 | – | pF | $V_{GS}=0V, V_{DS}=100V,$ $f=1\text{MHz}$ |
| Output capacitance | C_{oss} | – | 30 | – | | |
| Effective output capacitance, energy related ¹⁾ | $C_{o(er)}$ | – | 21 | – | | |
| Effective output capacitance, time related ²⁾ | $C_{o(tr)}$ | – | 88 | – | | |
| Turn- on delay time | $t_{d(on)}$ | – | 10 | – | ns | $V_{DD}=400V$ $V_{GS}=13V, I_D=3.2A,$ $R_G=6.8\Omega$ (see table 20) |
| Rise time | t_r | – | 8 | – | | |
| Turn- off delay time | $t_{d(off)}$ | – | 64 | – | | |
| Fall time | t_f | – | 11 | – | | |

1) $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

2) $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

Table 8 Gate charge characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|-----------------------|---------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Gate to source charge | Q_{GS} | – | 2.75 | – | nC | $V_{DD}=480V, I_D=3.2A,$ $V_{GS}=0$ to 10 V |
| Gate to drain charge | Q_{GD} | – | 12 | – | | |
| Gate charge, total | Q_G | – | 23 | – | | |
| Gate plateau voltage | $V_{plateau}$ | – | 5.5 | – | V | |

Table 8 Reverse diode characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|-------------------------------|-----------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Diode forward voltage | V_{SD} | – | 0.9 | – | V | $V_{GS}=0V, I_F=3.2A,$ $T_J=25^\circ C$ |
| Reverse recovery time | t_{rr} | – | 270 | – | ns | $V_R=400V, I_F=3.2A,$ $diF/dt=100A/\mu s$ |
| Reverse recovery charge | Q_{rr} | – | 2.0 | – | nC | |
| Peak reverse recovery current | I_{rrm} | – | 13 | – | A | (see table 22) |

5 Electrical characteristics diagrams

Table 10

| Power dissipation Non FullPAK | Power dissipation FULLPAK |
|----------------------------------|------------------------------|
| | |
| $P_{tot} = f(T_c)$ | $P_{tot} = f(T_c)$ |

Table 11

| Max. transient thermal impedance Non FullPAK | Max. transient thermal impedance Non FullPAK |
|---|---|
| | |
| $Z_{th(jc)} = f(t_p)$; parameter: $D = t_p/T$ | $Z_{th(jc)} = f(t_p)$; parameter: $D = t_p/T$ |

Table 12

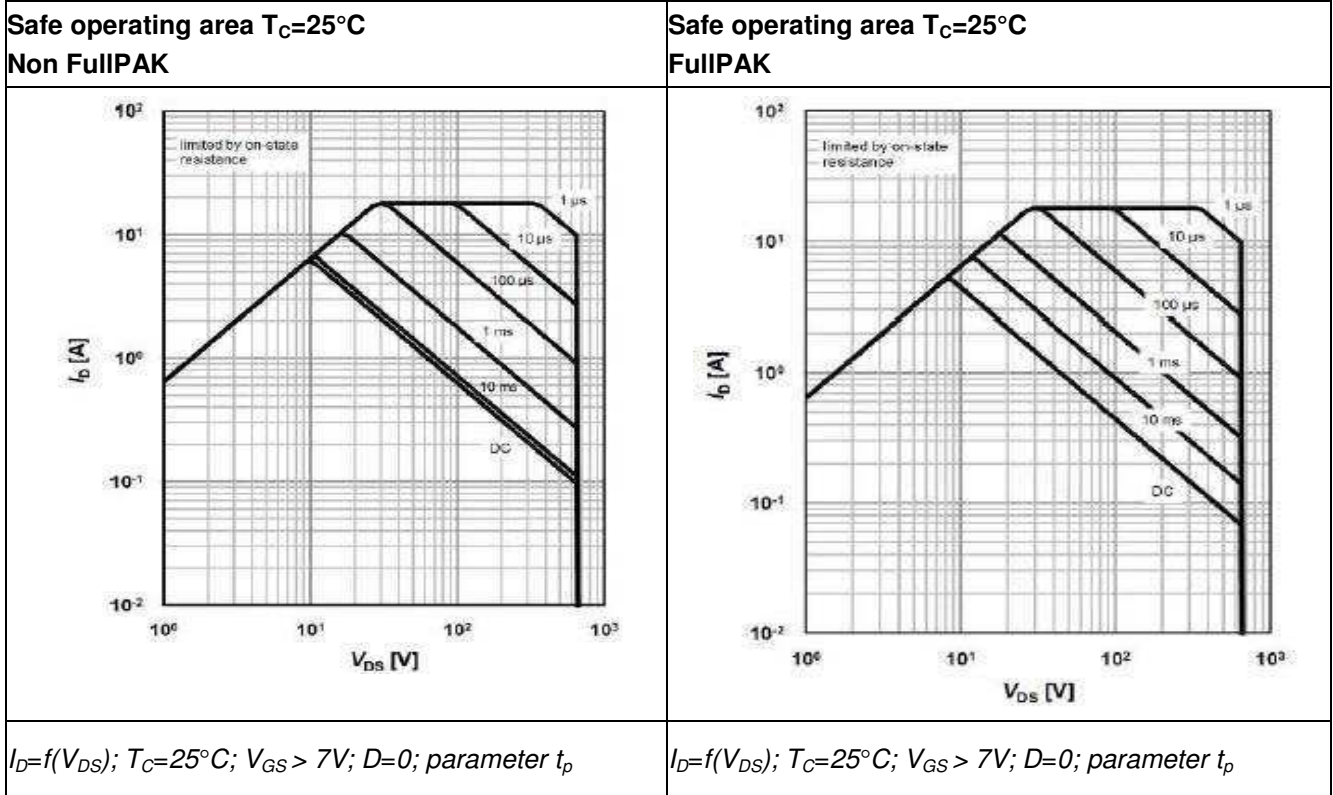


Table 13

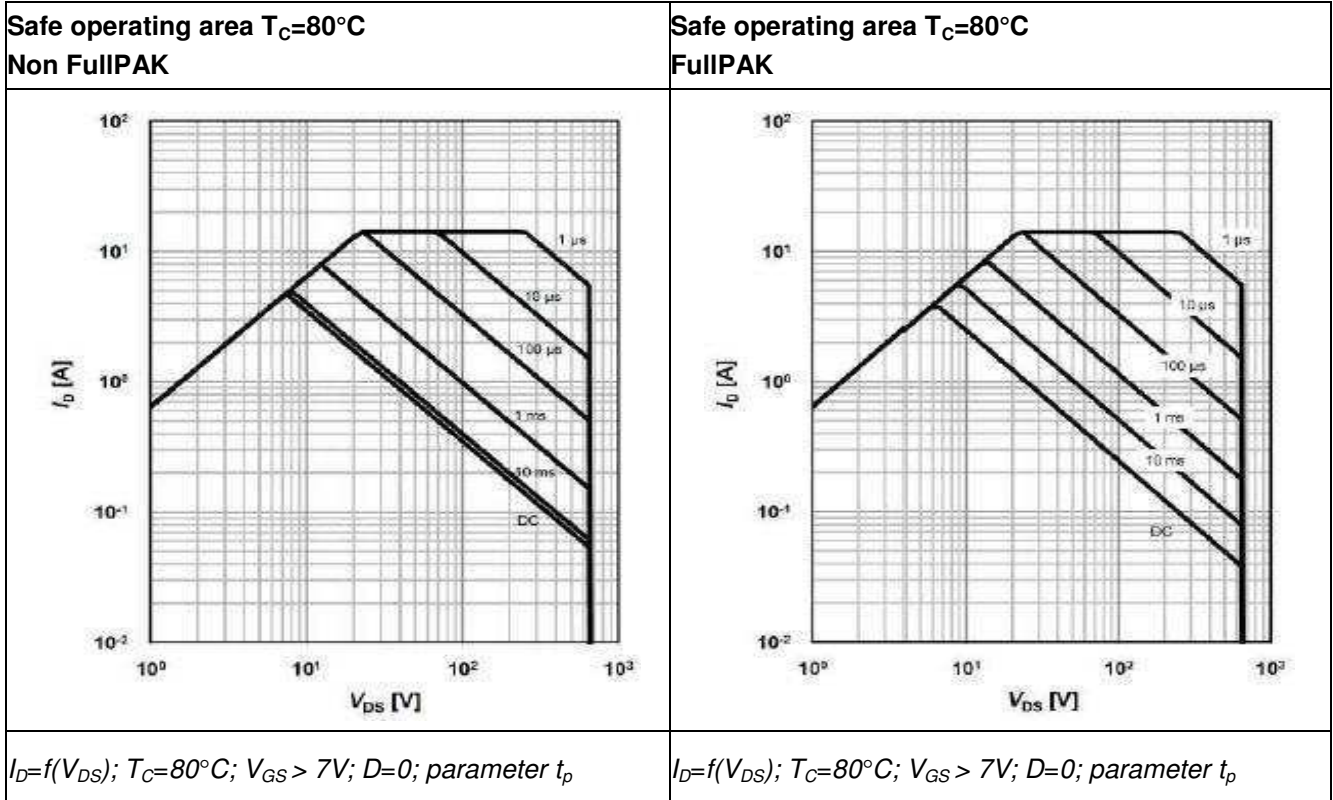


Table 14

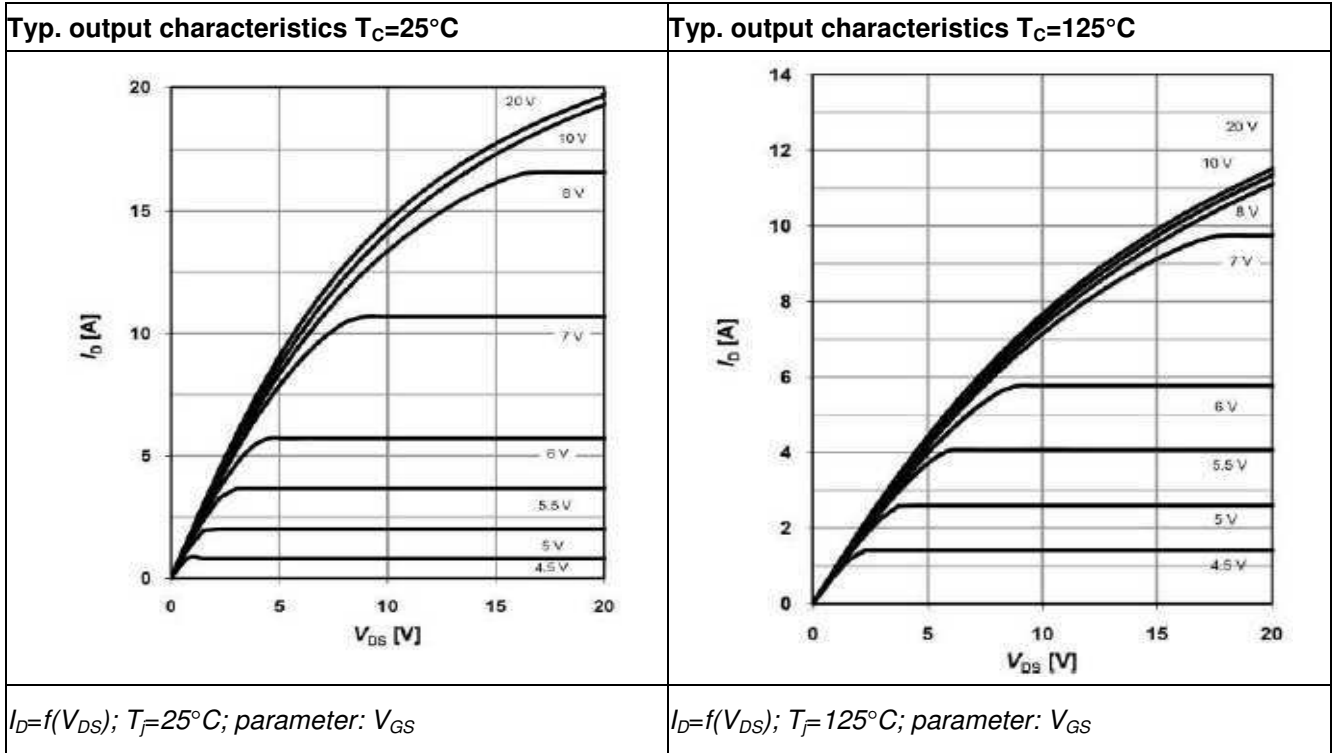


Table 15

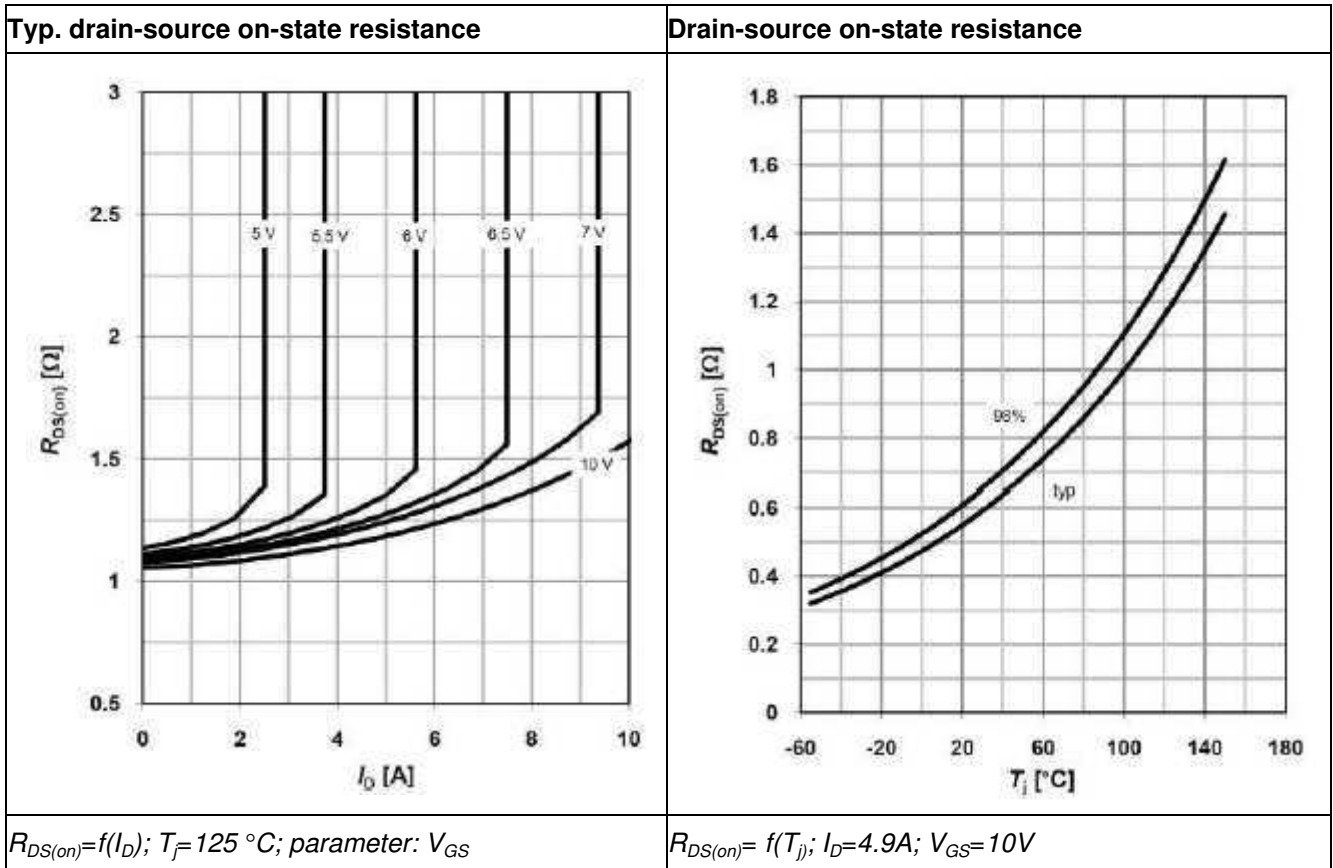


Table 16

| Typ. transfer characteristics | Typ. gate charge |
|---------------------------------|--|
| | |
| $I_D = f(V_{GS}); V_{DS} = 20V$ | $V_{GS} = f(Q_{gate}), I_D = 4.9 A \text{ pulsed}$ |

Table 17

| Avalanche energy | Drain-source breakdown voltage |
|---|--------------------------------------|
| | |
| $E_{AS} = f(T_j); I_D = 1.8 A; V_{DD} = 50 V$ | $V_{BR(DSS)} = f(T_j); I_D = 1.0 mA$ |

Table 18

| Typ. capacitances | Typ. C_{OSS} stored energy |
|--|---|
| <p>A semi-logarithmic plot showing capacitance C [pF] on the y-axis (log scale from 10⁰ to 10⁵) versus drain-source voltage V_{DS} [V] on the x-axis (linear scale from 0 to 600). Three curves are shown: C_{iss} (input capacitance) is constant at approximately 500 pF; C_{oss} (output capacitance) starts at ~10³ pF at 0V and decreases to ~10¹ pF at 600V; C_{rss} (reverse transfer capacitance) starts at ~10³ pF at 0V and drops sharply to ~10⁰ pF at 100V, then slightly increases to ~10¹ pF at 600V.</p> | <p>A linear plot showing stored energy E_{oss} [μJ] on the y-axis (linear scale from 0 to 4) versus drain-source voltage V_{DS} [V] on the x-axis (linear scale from 0 to 600). The curve shows that stored energy increases from 0 μJ at 0V to approximately 3.5 μJ at 600V.</p> |
| <p>$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$</p> | <p>$E_{OSS}=f(V_{DS})$</p> |

Table 19

| Forward characteristics of reverse diode |
|---|
| <p>A semi-logarithmic plot showing reverse current I_r [A] on the y-axis (log scale from 10⁻¹ to 10²) versus reverse drain-source voltage V_{SD} [V] on the x-axis (linear scale from 0 to 2). Two curves are shown for different temperatures: 125°C and 25°C. Both curves show an exponential-like increase in current with voltage, with the 125°C curve being significantly higher than the 25°C curve.</p> |
| <p>$I_F=f(V_{SD}); \text{parameter: } T_j$</p> |

6 Test circuits

Table 20 Switching times test circuit and waveform for inductive load

| Switching times test circuit for inductive load | Switching time waveform |
|---|-------------------------|
| | |

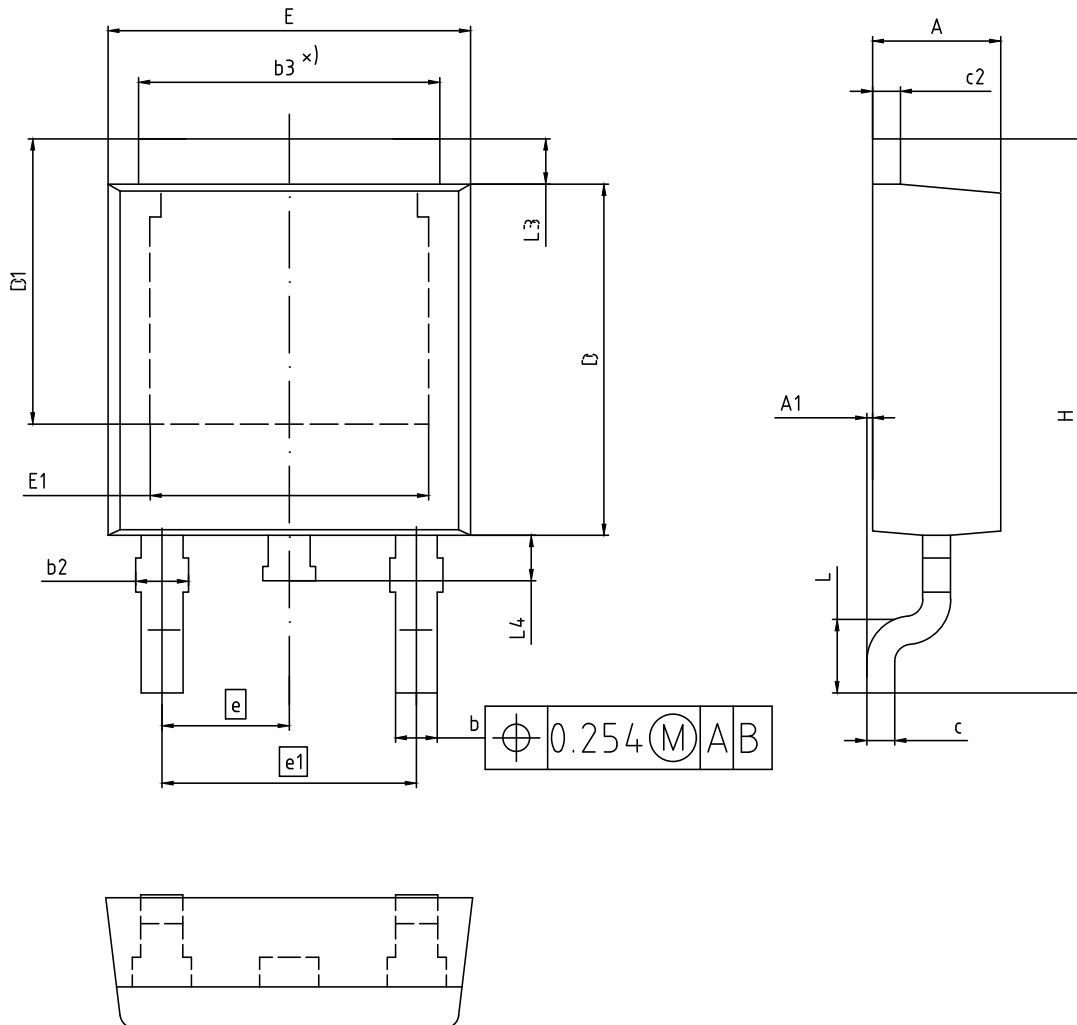
Table 21

| Unclamped inductive load test circuit | Unclamped inductive waveform |
|---------------------------------------|------------------------------|
| | |

Table 22

| Test circuit for diode characteristics | Diode recovery waveform |
|--|-------------------------|
| | |

7 Package outlines

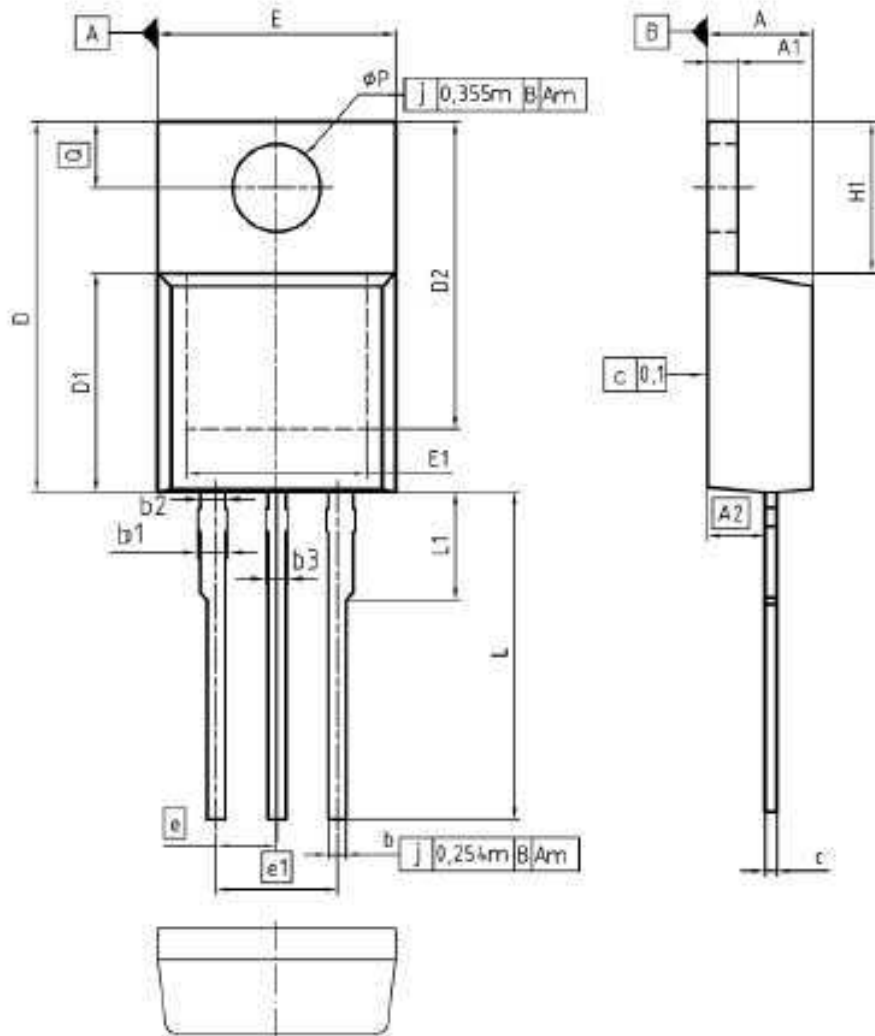


ALL DIMENSIONS REFER TO JEDEC STANDARD TO-252 AND DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

| DIMENSION | MILLIMETERS | |
|-----------|-------------|-------|
| | MIN. | MAX. |
| A | 2.16 | 2.41 |
| A1 | 0.00 | 0.15 |
| b | 0.64 | 0.89 |
| b2 | 0.65 | 1.15 |
| b3 | 4.95 | 5.50 |
| c | 0.46 | 0.61 |
| c2 | 0.40 | 0.98 |
| D | 5.97 | 6.22 |
| D1 | 5.02 | 5.84 |
| E | 6.35 | 6.73 |
| E1 | 4.32 | 5.50 |
| e | 2.29 | |
| e1 | 4.57 | |
| N | 3 | |
| H | 9.40 | 10.48 |
| L | 1.18 | 1.78 |
| L3 | 0.89 | 1.27 |
| L4 | 0.51 | 1.02 |

| |
|-------------------------------|
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| EUROPEAN PROJECTION |
| ISSUE DATE 01.04.2020 |

Figure 1 Outlines TO-252, dimensions in mm



| DIM | MILLIMETERS | | INCHES | |
|-------|-------------|-------|--------|-------|
| | MIN | MAX | MIN | MAX |
| A | 4.30 | 4.57 | 0.169 | 0.180 |
| A1 | 1.17 | 1.40 | 0.046 | 0.055 |
| A2 | 2.15 | 2.72 | 0.085 | 0.107 |
| b | 0.65 | 0.86 | 0.026 | 0.034 |
| b1 | 0.95 | 1.40 | 0.037 | 0.055 |
| b2 | 0.95 | 1.15 | 0.037 | 0.045 |
| b3 | 0.65 | 1.15 | 0.026 | 0.045 |
| c | 0.33 | 0.60 | 0.013 | 0.024 |
| D | 14.81 | 15.95 | 0.583 | 0.628 |
| D1 | 8.51 | 9.45 | 0.335 | 0.372 |
| D2 | 12.19 | 13.10 | 0.480 | 0.516 |
| E | 9.70 | 10.36 | 0.382 | 0.408 |
| E1 | 6.50 | 8.00 | 0.256 | 0.313 |
| e | 2.54 | | 0.100 | |
| e1 | 5.08 | | 0.200 | |
| N | 3 | | 3 | |
| H1 | 6.90 | 6.90 | 0.272 | 0.272 |
| L | 13.00 | 14.00 | 0.512 | 0.551 |
| L1 | - | 4.90 | - | 0.193 |
| phi P | 3.60 | 3.60 | 0.142 | 0.153 |
| phi | 2.60 | 3.00 | 0.102 | 0.118 |

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REVISION
05

Figure 2 Outlines TO220, dimensions in mm/inches

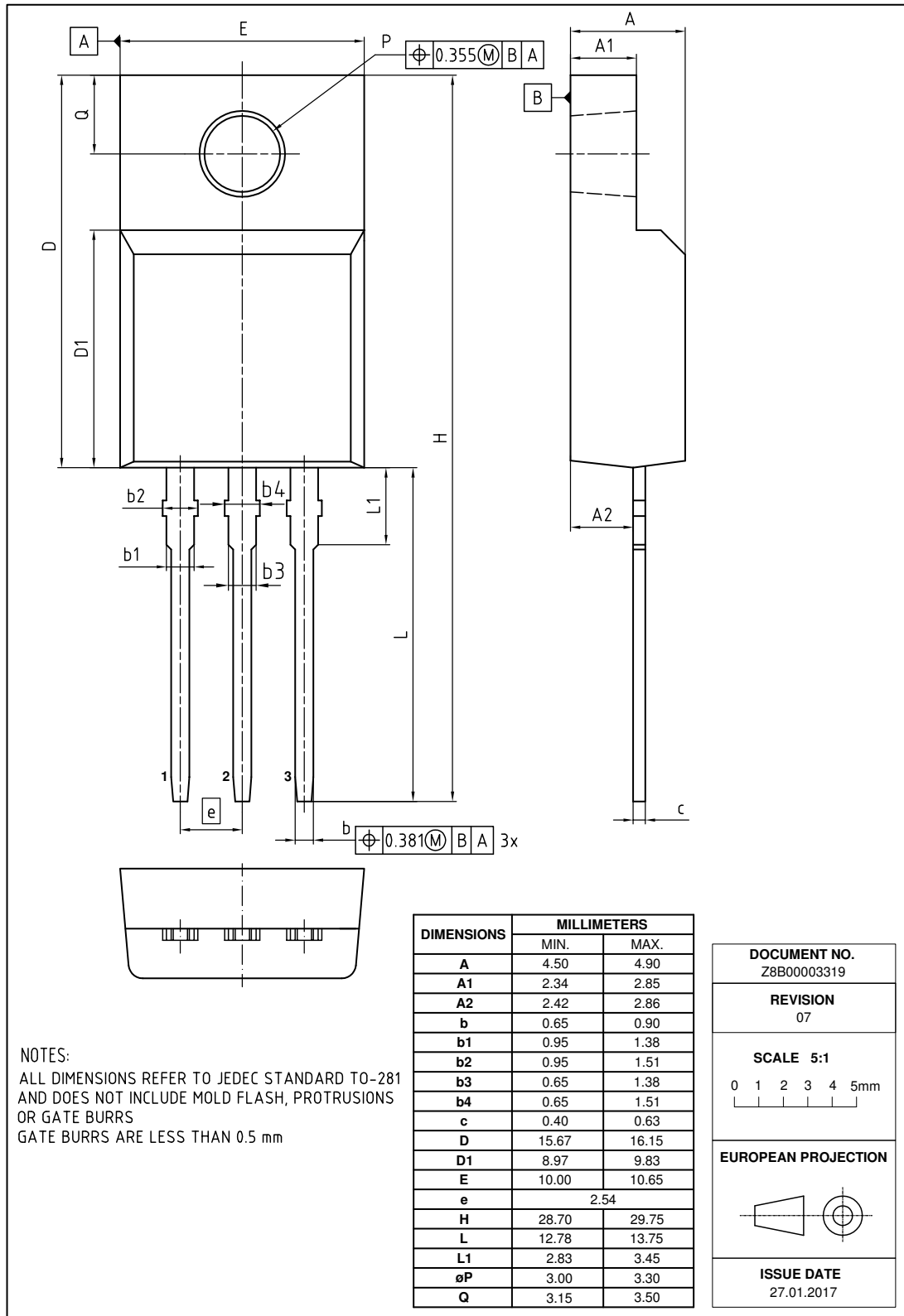


Figure 3 Outlines TO220 FullPAK, dimensions in mm

Revision History

IPx65R600E6

Revision: 2020-05-20, Rev. 2.4

Previous Revision

| Revision | Date | Subjects (major changes since last revision) |
|----------|------------|---|
| 2.2 | 2016-08-04 | Revised TO220 Full PAK package drawing on page 16 |
| 2.3 | 2018-03-04 | Outline PG-TO-220 FullPAK update |
| 2.4 | 2020-05-20 | Update of the package outlines TO-252 |

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